



Docket No.: SON-2810  
(PATENT)

**IN THE UNITED STATES PATENT AND TRADEMARK OFFICE**

In re Reexamination Application of:  
Yoshitaka Kayukawa et al.

Application No.: 10/647,217

Confirmation No.: 1901

Filed: August 26, 2003

Art Unit: 2138

For: SEMICONDUCTOR INTEGRATED CIRCUIT  
AND METHOD FOR TESTING SAME

Examiner: D. B. Gandhi

**AMENDMENT SUBMITTED WITH REQUEST FOR CONTINUED EXAMINATION**

MS RCE  
Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

Dear Sir:

**INTRODUCTORY COMMENTS**

In response to the Office Action dated January 29, 2007, finally rejecting claims 1-23, please amend the above-identified U.S. patent application as follows. This amendment is concurrently filed with a Request for Continued Examination as well as a petition for a two month extension of the time period for responding to the Action.

**Amendments to the Claims** are reflected in the listing of claims which begins on page 2 of this paper.

**Remarks/Arguments** begin on page 13 of this paper.